



Test report No. : 10812026H-E-R1
Page : 1 of 21
Issued date : July 21, 2015
Revised date : November 24, 2015
FCC ID : CGJ1152EA

RADIO TEST REPORT

Test Report No. : 10812026H-E-R1

Applicant : NIKON CORPORATION
Type of Equipment : Wireless Transmitter
Model No. : N1526
FCC ID : CGJ1152EA
Test regulation : FCC Part 15 Subpart E: 2015
(DFS test only)
Test Result : Complied

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6. This test report covers Radio technical requirements. It does not cover administrative issues such as Manual or non-Radio test related Requirements. (if applicable)
7. This report is a revised version of 10812026H-E. 10812026H-E is replaced with this report.

Date of test: June 25, 2015

Representative test engineer:

T. Shimada

Takumi Shimada
Engineer

Consumer Technology Division

Approved by:

T. Hatahara

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Leader

Consumer Technology Division



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SECTION 1: Customer information

Company Name : NEC Platforms, Ltd.
Address : 800, Shimomata, Kakegawa-shi, Shizuoka 436-8501, Japan
Telephone Number : +81-537-22-8276
Facsimile Number : +81-537-22-8236
Contact Person : Kouichi Sakurai

***Remarks:**

NIKON CORPORATION designates NEC Platforms, Ltd. as manufacturer of the product (Wireless Transmitter).

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Wireless Transmitter
Model No. : N1526
Serial No. : Refer to Clause 4.2
Rating : DC 5.0 V
Receipt Date of Sample : June 1, 2015
Country of Mass-production : Japan
Condition of EUT : Engineering prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT : No Modification by the test lab

2.2 Product Description

Model No: N1526 (referred to as the EUT in this report) is the Wireless Transmitter.

General Specification

Clock frequency(ies) in the system : 40 MHz (Crystal), 32.7 kHz (OSC)
Operating temperature : 0 deg. C to +40 deg. C

Radio Specification

Radio Type : Transceiver
Power Supply (inner) : DC 3.3 V

Specification of Wireless LAN (IEEE802.11b/g/a/n-20/n-40/11ac-20/11ac-40/11ac-80)

Specification of Wireless LAN (IEEE802.11b/g/n/20/n-40/11ac-20/11ac-40/11ac-80)						
Type of radio	IEEE802.11b	IEEE802.11g/n (20 M band)	IEEE802.11n (40 M band)	IEEE802.11a/n/ac (20 M band)	IEEE802.11n/ac (40 M band)	IEEE802.11ac (80 M band)
Frequency of operation (MHz)	2412 - 2462	2412 - 2462	2422 - 2452	5180 - 5240 5260 - 5320 * 5745 - 5825	5190 - 5230 5270 - 5310 * 5755 - 5795	5210 5290 * 5775
Type of modulation	DSSS (CCK, DQPSK, DBPSK)	OFDM-CCK (64QAM, 16QAM, QPSK, BPSK)		OFDM (64QAM, 16QAM, QPSK, BPSK, 256QAM(IEEE802.11ac only))		
Channel spacing	5 MHz			20 MHz	40 MHz	80 MHz
Antenna type	Antenna 0: Pattern Antenna Inverted L Type Antenna 1: Pattern Antenna Inverted L Type					
Antenna Gain	2.4GHz: 1 dBi 5GHz: 1 dBi					
Directional Antenna Gain	2.4 GHz: 4.01 dBi 5 GHz: 4.01 dBi					

* This test report applies to Wireless LAN (5 GHz Band [5260-5320 MHz , 5270-5310 MHz, and 5290 MHz]).

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SECTION 3: Scope of Report

This report only covers DFS requirement, as specified by the following referenced procedures.

SECTION 4: Test specification, procedures & results

4.1 Test Specification

Test Specification	:	FCC Part 15 Subpart E: 2015, final revised on November 23, 2015 *Some parts are effective on and after December 17, 2015 or December 23, 2015. The revision does not affect the test specification applied to the EUT.
Title	:	FCC 47CFR Part15 Radio Frequency Device Subpart E Unlicensed National Information Infrastructure Devices Section 15.407 General technical requirements
Test Specification	:	KDB905462 D02 UNII DFS Compliance Procedures New Rules v01r02
Title	:	COMPLIANCE MEASUREMENT PROCEDURES FOR UNLICENSED- NATIONAL INFORMATION INFRASTRUCTURE DEVICES OPERATING IN THE 5250-5350MHz AND 5470-5725MHz BANDS INCORPORATING DYNAMIC FREQUENCY SELECTION
Test Specification	:	KDB905462 D03 Client Without DFS New Rules v01r01
Title	:	U-NII CLIENT DEVICES WITHOUT RADAR DETECTION CAPABILITY
Test Specification	:	KDB905462 D04 Operational Modes for DFS Testing New Rules v01
Title	:	OPERATIONAL MODES SUGGESTED FOR DFS TESTING

FCC 15.31 (e)

This EUT provides stable voltage (DC 3.3 V) constantly to RF Part regardless of input voltage. Therefore, this EUT complies with the requirement.

FCC Part 15.203 Antenna requirement

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

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4.2 Procedures and results

Table 1: Applicability of DFS Requirements

Requirement	Operating Mode	Test Procedures & Limits	Deviation	Results
	Client without Radar Detection			
U-NII Detection Bandwidth	Not required	KDB905462 D02 UNII DFS Compliance Procedures New Rules v01r02	N/A	N/A
Initial Channel Availability Check Time	Not required	FCC15.407 (h)	N/A	N/A
		KDB905462 D02 UNII DFS Compliance Procedures New Rules v01r02		
		RSS-247 6.3		
Radar Burst at the Beginning of the Channel Availability Check Time	Not required	FCC15.407 (h)	N/A	N/A
		KDB905462 D02 UNII DFS Compliance Procedures New Rules v01r02		
		RSS-247 6.3		
Radar Burst at the End of the Channel Availability Check Time	Not required	FCC15.407 (h)	N/A	N/A
		KDB905462 D02 UNII DFS Compliance Procedures New Rules v01r02		
		RSS-247 6.3		
In-Service Monitoring for Channel Move Time, Channel Closing Transmission Time	Yes	FCC15.407 (h)	N/A	Complied
		KDB905462 D02 UNII DFS Compliance Procedures New Rules v01r02		
		RSS-247 6.3		
In-Service Monitoring for Non-Occupancy period	Yes *	FCC15.407 (h)	N/A	Complied
		KDB905462 D02 UNII DFS Compliance Procedures New Rules v01r02		
		RSS-247 6.3		
Statistical Performance Check	Not required	FCC15.407 (h)	N/A	N/A
		KDB905462 D02 UNII DFS Compliance Procedures New Rules v01r02		

Note: UL Japan, Inc.'s EMI Work Procedures No. 13-EM-W0422.

*Although this test was not required in FCC, KDB 905462 D02, it was performed as additional test.

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Table 2 DFS Detection Thresholds for Master Devices and Client Devices With Radar Detection

Maximum Transmit Power	Value (See Notes 1,2, and 3)
≥ 200 milliwatt	-64 dBm
< 200 milliwatt and power spectral density < 10dBm/MHz	-62 dBm
< 200 milliwatt that do not meet the power spectral density requirement	-64 dBm
Note 1: This is the level at the input of the receiver assuming a 0 dBi receive antenna. Note 2: Throughout these test procedures an additional 1 dB has been added to the amplitude of the test transmission waveforms to account for variations in measurement equipment. This will ensure that the test signal is at or above the detection threshold level to trigger a DFS response. Note 3: EIRP is based on the highest antenna gain. For MIMO devices refer to KDB Publication 662911 D01.	

Table 3 DFS Response Requirement Values

Parameter	Value
Non-occupancy period	Minimum 30 minutes
Channel Availability Check Time	60 seconds
Channel Move Time	10 seconds See Note 1
Channel Closing Transmission Time	200 milliseconds + an aggregate of 60 milliseconds over remaining 10 second period. See Notes 1 and 2
U-NII Detection Bandwidth	Minimum 100% of the U-NII 99% transmission power bandwidth See Note 3
Note 1: Channel Move Time and the Channel Closing Transmission Time should be performed with Radar Type 0. The measurement timing begins at the end of the Radar Type 0 burst. Note 2: The Channel Closing Transmission Time is comprised of 200 milliseconds starting at the beginning of the Channel Move Time plus any additional intermittent control signals required to facilitate a Channel move (an aggregate of 60 milliseconds) during the remainder of the 10 second period. The aggregate duration of control signal will not count quiet periods in between transmissions. Note 3: During the U-NII Detection Bandwidth detection test, radar type 0 should be used. For each frequency step the minimum percentage of detection is 90 percent. Measurements are performed with no data traffic.	

Table 4 Short Pulse Radar Test Waveform

Radar Type	Pulse Width (μsec)	PRI (μsec)	Number of Pulses	Minimum Percentage of Successful Detection	Minimum Number of Trials
0	1	1428	18	See Note 1	See Note 1
1	1	Test A: 15 unique PRI values randomly selected from the list of 23 PRI values in Table 5a Test B: 15 unique PRI values randomly selected within the range of 518-3066 μsec, with a minimum increment of 1 μsec, excluding PRI values selected in Test A	Roundup $\{(1/360) * (19 * 10^6 / \text{PRI}_{\text{μsec}})\}$	60%	30
2	1-5	150-230	23-29	60%	30
3	6-10	200-500	16-18	60%	30
4	11-20	200-500	12-16	60%	30
Aggregate (Rader Types 1-4)				80%	120
Note 1: Short Pulse Radar Type 0 should be used for the detection bandwidth test, channel move time, and channel closing time tests.					

Table 5 Long Pulse Radar Test Waveform

Radar Type	Pulse Width (μsec)	Chip Width (MHz)	PRI (μsec)	Number of Pulses per Burst	Number of Burst	Minimum Percentage of Successful Detection	Minimum Number of Trials
5	50-100	5-20	1000-2000	1-3	8-20	80%	30

Table 6 Frequency Hopping Radar Test Waveform

Radar Type	Pulse Width (μsec)	PRI (μsec)	Pulse per Hop (kHz)	Hopping Rate (kHz)	Hopping Sequence Length (msec)	Minimum Percentage of Successful Detection	Minimum Number of Trials
6	1	333	9	0.333	300	70%	30

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4.3 Test Location

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	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	4.0 x 4.5 x 2.7m	4.0 x 4.5 m	-
No.6 measurement room	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	8.0 x 4.6 x 2.8m	2.4 x 2.4m	-
No.11 measurement room	-	6.2 x 4.7 x 3.0m	4.8 x 4.6m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

4.4 Uncertainty

The following uncertainties have been calculated to provide a confidence level of 95 % using a coverage factor $k = 2$.
Time Measurement uncertainty for this test was: ($\pm$) 0.012 %

4.5 Data of DFS test, Test instruments of DFS, Test set up

Refer to APPENDIX.

SECTION 5: Operation of E.U.T. during testing

5.1 Operating Modes

For FCC the EUT operates over the 5260-5320MHz, 5270-5310MHz and 5290MHz ranges.

The EUT has the Client mode without Radar Detection.

The highest power level is 17.31dBm EIRP in the 5260-5320MHz band.

Power level(EIRP) of the EUT[dBm]

Output Power (Max)		
20Mband	40Mband	80Mband
17.30	17.31	14.14

Power spectral density level of the EUT[dBm/MHz]

Output Power (Max)		
20Mband	40Mband	80Mband
2.83	-0.93	-6.17

*Refer to 10812026H-C-R1, FCC Part 15E (FCC 15.407) report for other parts than DFS.

The channel-loading of approximately 17% or greater was used for testing, and its test data was transferred from the Master Device to the Client Device for all test configurations.

The EUT utilizes the 802.11a/n/ac architecture, with a 20MHz, 40MHz and 80MHz channel bandwidth.

The FCC ID for the Master Device used with EUT for DFS testing is LDK102087.

The rated output power of the Master unit is >200mW(23dBm). Therefore the required interference threshold level is -64 dBm. After correction for antenna gain and procedural adjustments, the required conducted threshold at the antenna port is $-64 + 1 + 0 = -63.0$ dBm (threshold level + additional 1dB + antenna gain).

It is impossible for users to change DFS control, because the DFS function is written on the firmware and users cannot access it.

The EUT was set by the software as follows:

Software name & version: iperf Version: 2.0.5 (08.Jul 2010)

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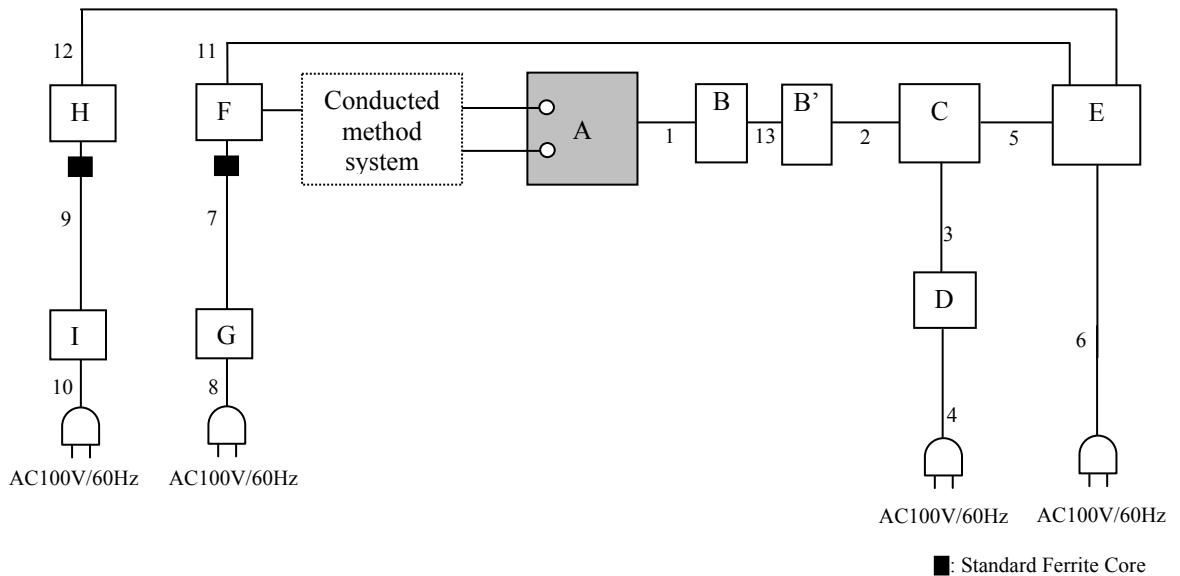
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5.2 Configuration and peripherals



Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Wireless Transmitter	N1526	No.3	NEC Platforms, Ltd.	EUT
B	Jig Board	-	-	NEC Platforms, Ltd.	-
C	Laptop PC	FMVNA7BE4	R8800679	FUJITSU	-
D	AC Adapter	ADP-80NB	10268063C	FUJITSU	-
E		FX-08IS	07DK01286C	PLANEX COMMUNICATIONS INC.	-
F	Wireless LAN access point	AIR-CAP3702EA-K9	FTX182276QC	CISCO	-
G	AC adapter	AA25480L	ALD030406GR	CISCO	-
H	Laptop PC	T410	R8-D74HD	lenovo	-
I	AC Adapter	92P1160	11S92P1160ZIZBGH 6B6DKV	lenovo	-

List of cables used

No.	Name	Length (m)	Shield		Remark
			Cable	Connector	
1	Flat Cable	0.03	Unshielded	Unshielded	-
2	USB Cable	1.50	Shielded	Shielded	-
3	DC Cable	1.90	Unshielded	Unshielded	-
4	AC Cable	1.80	Unshielded	Unshielded	-
5	LAN Cable	3.00	Unshielded	Unshielded	-
6	AC Cable	1.80	Unshielded	Unshielded	-
7	DC Cable	1.90	Unshielded	Unshielded	-
8	AC Cable	2.10	Unshielded	Unshielded	-
9	DC Cable	1.80	Unshielded	Unshielded	-
10	AC Cable	0.80	Unshielded	Unshielded	-
11	LAN Cable	5.00	Unshielded	Unshielded	-
12	LAN Cable	3.00	Unshielded	Unshielded	-
13	Signal Cable	0.40	Unshielded	Unshielded	-

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5.3 Test and Measurement System

SYSTEM OVERVIEW

The measurement system is based on a conducted test method.

The software selects waveform parameters from within the bounds of the signal type on a random basis using uniform distribution. The short pulse types 1, 2, 3, and 4, the long pulse type 5, and the frequency hopping type 6 parameters are randomized at run-time.

The signal monitoring equipment consists of a spectrum analyzer with the capacity to display 8001 bins on the horizontal axis. A time-domain resolution of 2 msec/bin is achievable with a 16 second sweep time, meeting the 10 seconds short pulse reporting criteria. The aggregate ON time is calculated by multiplying the number of bins above a threshold during a particular observation period by the dwell time per bin, with the analyzer set to peak detection.

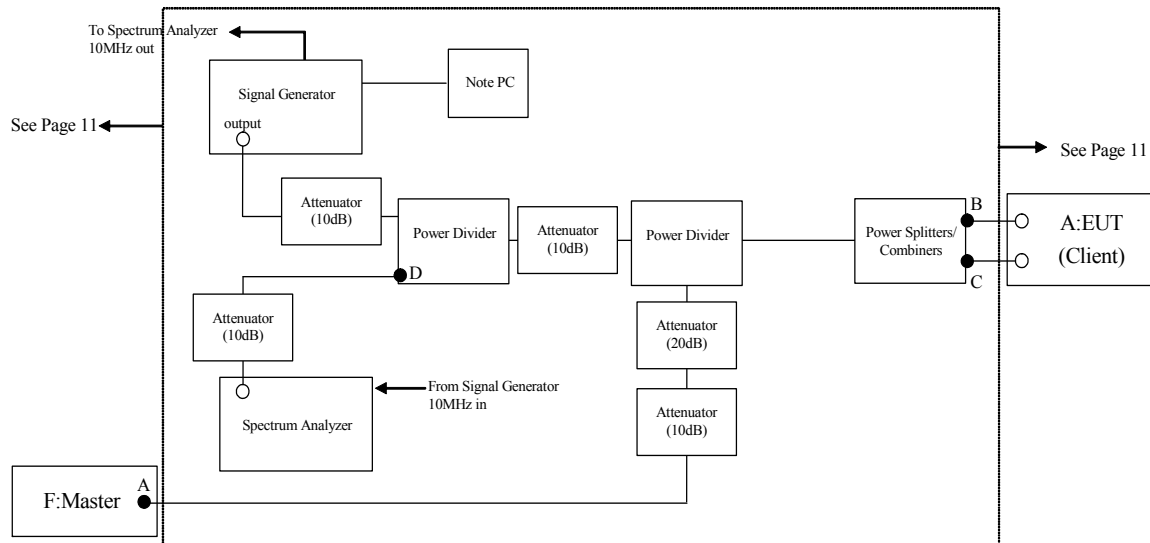
FREQUENCY HOPPING RADAR WAVEFORM GENERATING SUBSYSTEM

The first 100 frequencies are selected out of the hopping sequence of the randomized 475 hop frequencies.

Only a *Burst* that has the frequency falling within the receiver bandwidth of the tested U-NII device is selected among those frequencies. (Frequency-domain simulation). The radar waveform generated at the start time of the selected *Burst* (Time-domain simulation) is download to the Signal Generator.

If all of the randomly selected 100 frequencies do not fall within the receiver bandwidth of the U-NII device, the radar waveform is not used for the test.

CONDUCTED METHODS SYSTEM BLOCK DIAGRM



MEASUREMENT SYSTEM FREQUENCY REFERENCE

Lock the signal generator and the spectrum analyzer to the same reference sources as follows: Connect the 10MHz OUT on the signal generator to the 10MHz IN on the spectrum analyzer and set the spectrum analyzer 10MHz In to On.

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SYSTEM CALIBRATION

Step 1: Set the system as shown in Figure 3 of KDB905462 D02 7.2.2.

Step 2: Adjust each attenuator to fulfill the following three conditions:

- WLAN can be communicated, and
- Rader detection threshold level is bigger than Client Device traffic level on the spectrum analyzer, and
- Master Device traffic level is not displayed on the spectrum analyzer.

Step 3: Terminate 50 ohm at B, C and D points, and connect the spectrum analyzer to the point A. (See the figure on page 13)

At the point A, adjust the signal generator and spectrum analyzer to the center frequency of the channel to be measured.

Download the applicable radar waveforms to the signal generator. Select the radar waveform, trigger a burst manually and measure the amplitude on the spectrum analyzer. Readjust the amplitude of the signal generator as required so that the peak level of the waveform is at a displayed level equal to the required or desired interference detection threshold.

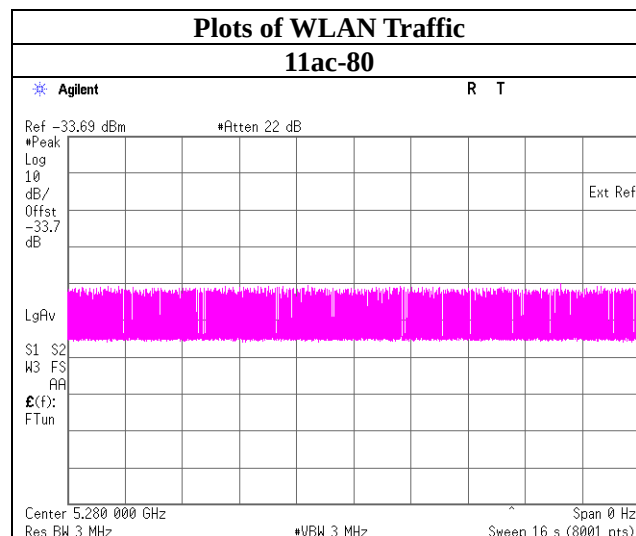
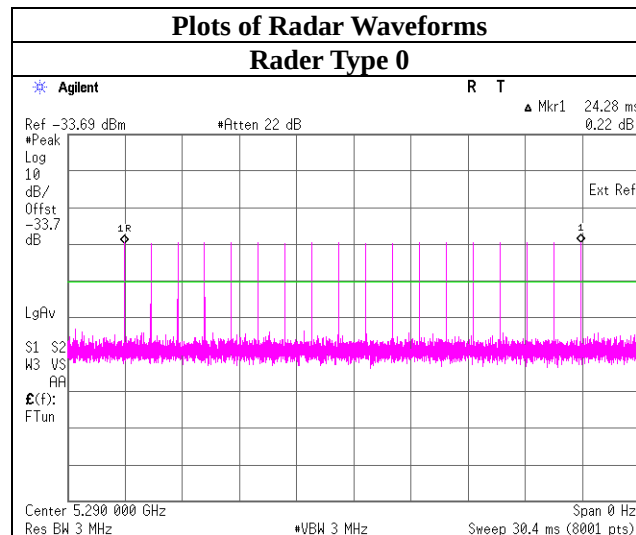
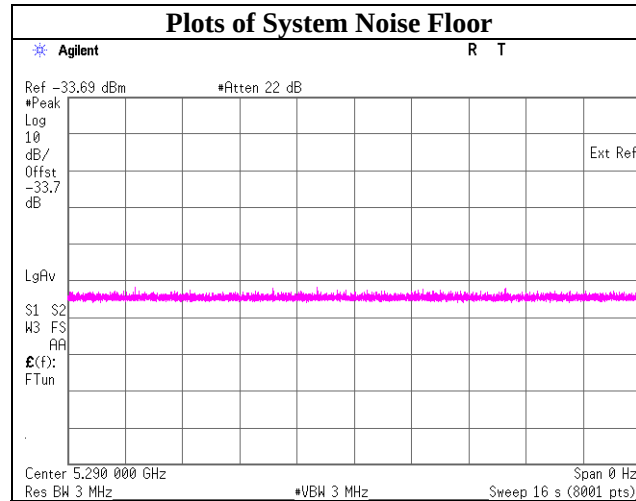
Separate signal generator amplitude settings are determined as required for each radar type.

Step 4: Without changing any of the instrument settings, restore the system setting to Step 2 and adjust the Reference Level Offset of the spectrum analyzer to the level at Step 3.

By taking the above steps 1 to 4, the spectrum analyzer displays the level of the signal generator as received at the antenna ports of the Master Device.

See Clause 5.4 for Plots of Noise, Rader Waveforms, and WLAN signals.

5.4 Plots of Noise, Radar Waveforms, and WLAN signals



SECTION 6: Channel Move Time, Channel Closing Transmission Time

6.1 Operating environment

Test place : Ise EMC Lab.No.7 shielded room
Date : 06/25/2015
Temperature/ Humidity : 23deg. C / 62% RH
Engineer : Takumi Shimada
Mode : 11ac-80

6.2 Test Procedure

Transmit the data from the Master Device to the Client Device on the test Channel for the entire period of the test. The Radar Waveform generator sends a Burst of pulses for one of the Radar Types 0 at levels defined on the Operating Channel. An additional 1 dB is added to the radar test signal to ensure it is at or above the DFS Detection Threshold, accounting for equipment variations/errors. Observe the transmissions of the EUT at the end of the radar Burst on the Operating Channel for duration greater than 10 seconds.

6.3 Test data

11ac-80

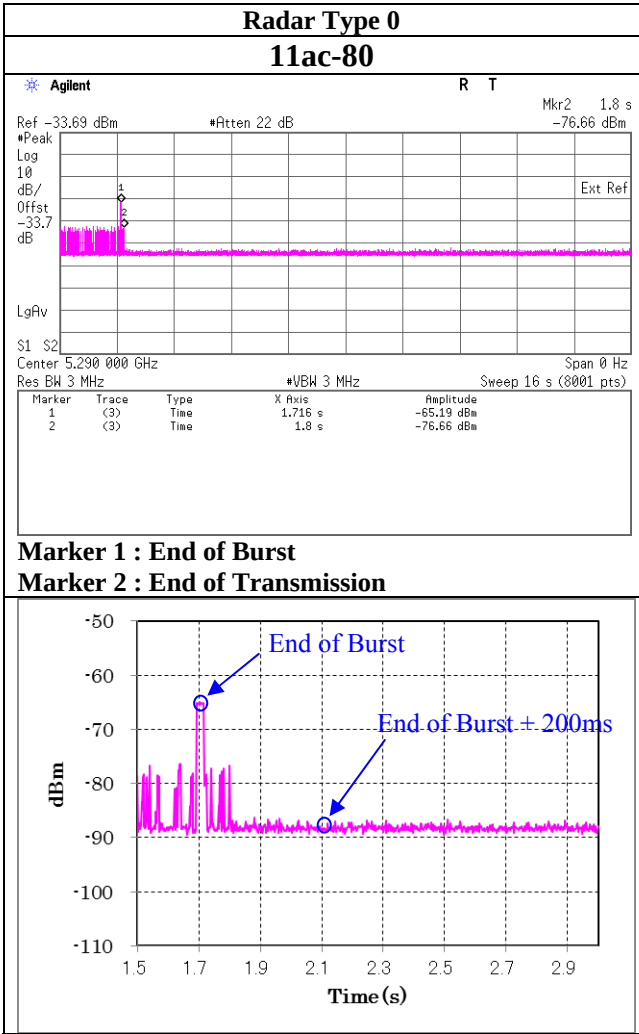
Test Item	Unit	Measurement Time	Limit	Results
Channel Move Time *1)	[sec]	0.084	10.000	Pass
Channel Closing Transmission Time *2)	[msec]	0	60	Pass

*1) Channel Move Time is calculated as follows:

(Channel Move Time) = (End of Transmission) - (End of Burst) = 1.8-1.716

*2) Channel Closing Transmission Time is calculated from (End of Burst + 200msec) to (End of Burst + 10sec)

(Channel Closing Transmission Time) = (Number of analyzer bins showing transmission) × (dwell time per bin)
= 0 × 2[msec]



6.4 Test result

Test result: Pass

SECTION 7: Non-Occupancy Period

7.1 Operating environment

Test place	Ise EMC Lab. No.7 shielded room
Date	06/25/2015
Temperature/ Humidity	23deg. C / 62% RH
Engineer	Takumi Shimada
Mode	11ac-80

7.2 Test Procedure

The following two tests are performed:

- 1). Transmit the data from the Master Device to the Client Device on the test Channel for the entire period of the test. The Radar Waveform generator sends a Burst of pulses for Radar Types 0 at levels defined on the Operating Channel. An additional 1 dB is added to the radar test signal to ensure it is at or above the DFS Detection Threshold, accounting for equipment variations/errors.
Observe the transmissions of the EUT after the Channel Move Time on the Operating Channel for duration greater than 30 minutes.
- 2). Transmit the data from the Master Device to the Client Device on the test Channel for the entire period of the test. Observe the transmissions of the EUT on the Operating Channel for duration greater than 30 minutes after the Master Device is shut off.

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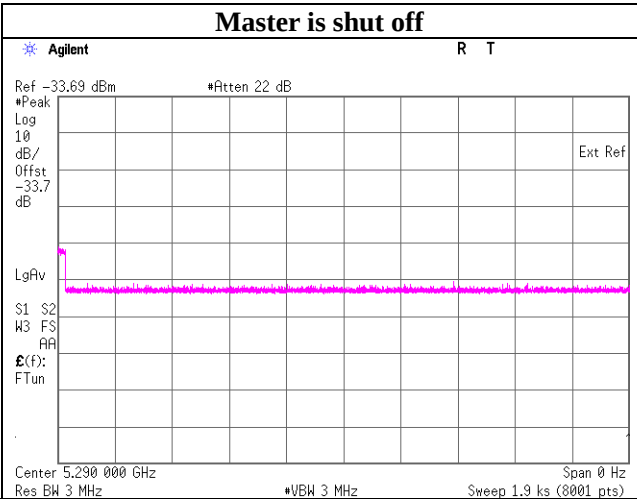
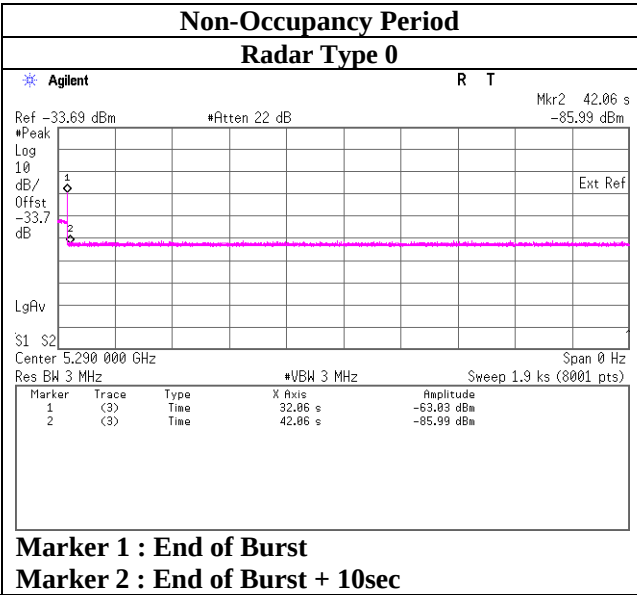
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7.3 Test data



7.4 Test result

Test result: Pass

APPENDIX 1: Test instruments

EMI Test Equipment

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
MSA-04	Spectrum Analyzer	Agilent	E4448A	US44300523	DFS	2014/11/12 * 12
EST-48 *1)	Signal Generator	Agilent	E4438C	MY45090353	DFS	2014/12/19 * 12
MPD-01	PowerDivider DC to 26.5GHz	Agilent	11636B	52258	DFS	2015/03/10 * 12
MPSC-04	Power Splitters/Combiners	Mini-Circuit	ZFSC-2-10G	0326	DFS	2014/09/26 * 12
MPSC-07	Power Splitters/Combiners	Pasternack Enterprises	ZFRSC-123-S+	ZFRSC-123- 00232	DFS	Pre Check
MAT-20	Attenuator(10dB)(above 1GHz)	HIROSE ELECTRIC CO.,LTD.	AT-110	-	DFS	2015/01/08 * 12
MAT-56	Attenuator(10dB)	Suhner	6810.19.A	-	DFS	2015/01/08 * 12
MAT-57	Attenuator(10dB)	Suhner	6810.19.A	-	DFS	2015/01/08 * 12
MAT-58	Attenuator(10dB)	Suhner	6810.19.A	-	DFS	2015/01/09 * 12
MAT-59	Attenuator(20dB)	Suhner	6820.19.A	-	DFS	Pre Check
MCC-183	Microwave Cable	Junkosha	MMX221- 00500DMSDMS	1502S310	DFS	Pre Check
MCC-172	Microwave Cable	Junkosha	MWX221	1409S495	DFS	2015/03/04 * 12
MCC-174	Microwave Cable	Junkosha	MWX221	1409S497	DFS	2015/03/04 * 12
COTS-MDFS- 01	Signal Studio Software for DFS	Agilent	N7620A-101	5010-7739	DFS	-
COTS-MDFS- 02	Radar Generating Software for DFS	Agilent	-	-	DFS	-
MOS-34	Thermo-Hygrometer	Custom	CTH-201	3401	DFS	2015/01/13 * 12

***1) Signal generator is only used to generate radar test signal, and the wave form is confirmed with spectrum analyzer every time before the test.**

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

DFS: Dynamic Frequency Selection

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